

**ARQ-LVP001****RAD-HARD Octal 500 Mbps Bus LVDS Repeater****FEATURES**

- 500.0 Mbps low jitter fully differential data path
- 250 MHz clock channel
- 3.3V power supply
- CMOS/TTL compatible inputs
- Low power consumption
- 24mA output driver short circuit (OUT+, OUT-)
- Cold sparing on all pins
- 3.5ns Propagation delay in temperature range
- Extended LVDS Input Common Mode [-4;5]V
- Receiver input threshold $\leq \pm 100$ mV
- 25mV (typ.) Input hysteresis
- Fail-safe protection circuit
- Radiation tolerant: 300 Krad(Si)
- Latch-up free up to 60 MeVcm²/mg
- ESD tolerance: 8KV
- Packaging: 48-pin Ceramic Quad Flat Pack (CQFP)
- ANSI TIA/EIA 644a LVDS Standard Compliant
- Space level

DESCRIPTION

ARQUIMEA's ARQ-LVP001 device is an Octal Bus Repeater for Low Voltage Differential Signals (LVDS) intended for low power and high-speed operation. Data paths are fully differential from input to output for low noise generation and low pulse width distortion. LVDS I/O enables high speed data transmission for point-to-point or multi-drop interconnects. This device is designed for use as a high speed differential repeater.

The ARQ-LVP001 is a repeater designed specifically for the bridging of multiple backplanes in a system. The ARQ-LVP001 utilizes low voltage differential signaling to deliver high speed while consuming minimal power with reduced EMI. The ARQ-LVP001 repeats signals between backplanes and accepts or drives signals onto the local bus.

The individual LVDS outputs can be put into Tri-State by use of the enable pins.

All pins have Cold Spare buffers. These buffers will be high impedance when VDD is tied to VSS.

The extended common mode range allows high voltage drops between ground planes without affecting performance.

APPLICATIONS

The ARQ-LVP001 provides the basic bus repeater function. The device operates as a 9 channel LVDS buffer (including Clock). Repeating the signal restores the LVDS amplitude, allowing it to drive another media segment. This allows isolation of segments or long distance applications.

The intended application of these devices and signaling technique is for both spacewire point-to-point baseband (single termination) and multipoint (double termination) data transmissions over controlled impedance media.

The transmission media may be printed-circuit board traces, backplanes, or cables.

RADIATION HARDENING

PARAMETER	MIN	TYP	MAX	UNIT	COMMENTS
TID	300	-	-	Krad	Only validated on former design ARQ-LVR001
SEL	60	-	-	MeVcm ² /mg	
SEE performance for a GEO orbit	1E-13 TBC	-	-	Err/Bit/day	

More information about radiation hardening features and radiation test conditions is available under request.

AVAILABLE OPTIONS

PRODUCT	QUALITY LEVEL	PACKAGE (*)	OPERATING TEMPERATURE	ORDERING NUMBER	VARIANT DETAIL	TRANSPORT MEDIA
ARQ-LVP001	Standard	48 pin CQFP	-55°C to 125°C	ARQ-LVP001-02	Without Fail-Safe	50-pieces tray
ARQ-LVP001	Standard	48 pin CQFP	-55°C to 125°C	ARQ-LVP001-03		50-pieces tray
ARQ-LVP001	ESCC9000	48 pin CQFP	-55°C to 125°C	ARQ-LVP001S03		50-pieces tray

(*) Other packaging options, including raw die format, are also available under request.

ARQ_12104_DSH_004_Issue_02, Date: 10-09-2017

The information contained herein is as of publication issue. Production processing does not necessarily include testing of all parameters. This documentation is not contractual and content delivery cannot be considered as an offer or contract. Under this document, the Company assumes no obligation towards third parties, liability or guarantee whatsoever.



INDEX

FEATURES.....	1
DESCRIPTION.....	1
APPLICATIONS.....	1
RADIATION HARDENING.....	1
AVAILABLE OPTIONS.....	1
OVERVIEW.....	3
BLOCK DIAGRAM.....	3
ABSOLUTE MAXIMUM RATINGS.....	4
RECOMMENDED OPERATING CONDITIONS.....	4
ELECTRICAL CHARACTERISTICS.....	5
AC SWITCHING CHARACTERISTICS.....	6
APPLICATIONS INFORMATION.....	8
PINOUT DESCRIPTION.....	9
PACKAGE.....	10
QUALITY STANDARDS.....	11
IMPORTANT NOTICE.....	12
REVISION HISTORY.....	13
CONTACT AND ORDERS:.....	14

GLOSSARY

BER	<i>Bit Error Ratio</i>
CMRR	<i>Common Mode Rejection Ratio</i>
CQFP	<i>Ceramic Quad Flat Pack</i>
ESD	<i>Electrostatic Discharge</i>
GEO	<i>Geostationary Earth Orbit</i>
IC	<i>Integrated Circuit</i>
I/O	<i>Input/Output</i>
LET	<i>Linear Energy Transfer</i>
LVDS	<i>Low Voltage Differential Signaling</i>
LVTTL	<i>Low Voltage Transistor-Transistor Logic</i>
PSRR	<i>Power Supply Rejection Ratio</i>
RL	<i>Load Resistor</i>
SEE	<i>Single Event Effect</i>
SEL	<i>Single Event Latch-up</i>
TID	<i>Total Ionizing Dose</i>
tf	<i>Fall Time</i>
tr	<i>Rise Time</i>
TTL	<i>Transistor-Transistor Logic</i>
VCM	<i>Common-mode voltage</i>
VID	<i>Differential Input Voltage</i>
VOS	<i>Offset voltage</i>
VT	<i>Differential output voltage</i>

ARQ_12104_DSH_004_Issue_02, Date: 10-09-2017

The information contained herein is as of publication issue. Production processing does not necessarily include testing of all parameters. This documentation is not contractual and content delivery cannot be considered as an offer or contract. Under this document, the Company assumes no obligation towards third parties, liability or guarantee whatsoever.



OVERVIEW

The ARQ-LVP001 provides the basic bus repeater function. The device operates as a 9 channel LVDS buffer. Repeating the signal restores the LVDS amplitude, allowing it to drive another media segment. This allows for isolation of segments or long distance applications. The intended application of these devices and signaling technique is for both point-to-point baseband (single termination) and multipoint (double termination) data transmissions over controlled impedance media.

BLOCK DIAGRAM

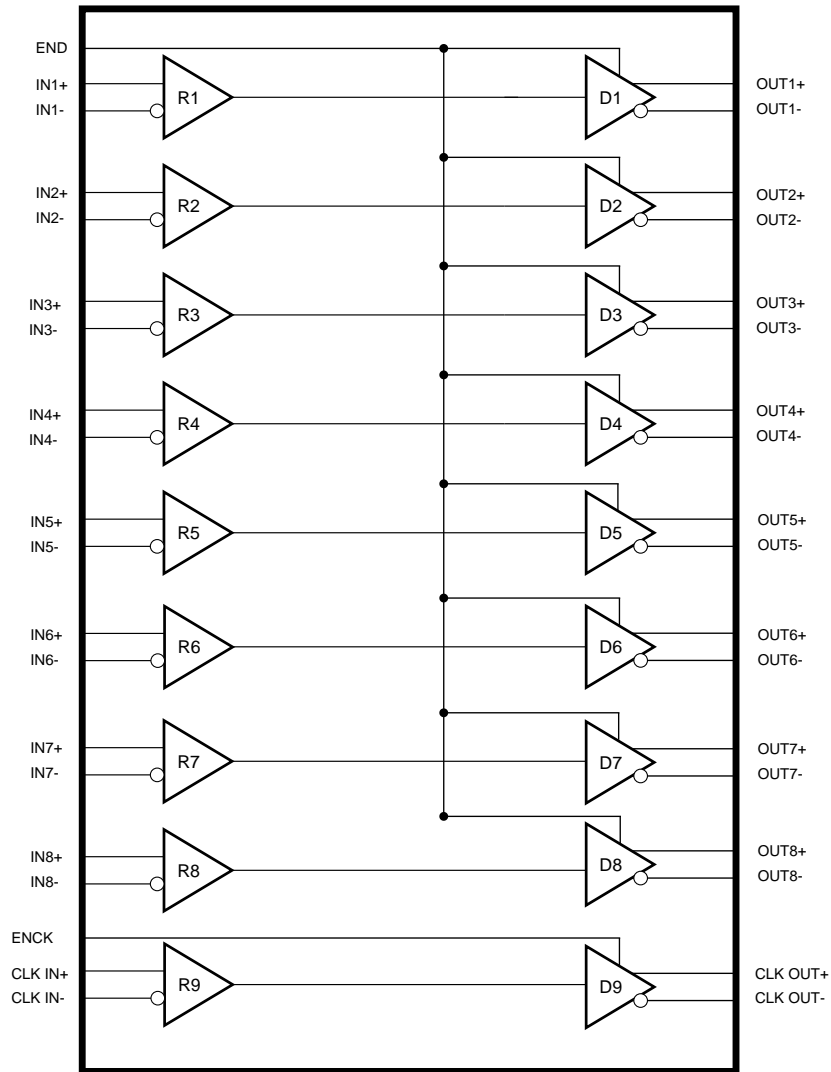


Figure 1: Block diagram

**ABSOLUTE MAXIMUM RATINGS**

SYMBOL	PARAMETER	VALUE
V _{DD}	DC supply voltage	-0.5 to 4.6V
V _I	TTL/CMOS Input Voltage	-0.5V to 6V
V _{IN}	LVDS Input Voltage	-5V to 6V
T _{STG}	Storage temperature	-65 to +150°C
T _J	Maximum junction temperature	+175°C
T _C	Maximum Case temperature	+125°C
ESD	ESD Last Passing Voltage – HBM	8kV
P _D	Power dissipation	400mW

Table 1: Absolute Maximum Rating

Note: Stresses outside the listed absolute maximum ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other condition beyond limits indicated in the operational sections of this specification is not recommended. Exposure to absolute maximum rating conditions for extended periods may affect device reliability and performance.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	VALUE
V _{DD}	Power supply voltage	3.0 to 3.6V
V _{IN}	DC input voltage, logic inputs (END or ENCK)	0 to 5V
	DC input voltage, receiver inputs	-4.6V to 5.6V
V _{CM}	LVDS Input Common Mode Voltage	-4V to 5V
T _C	Case temperature range	-55 to +125 °C

Table 2: Recommended Operating Conditions

ARQ_12104_DSH_004_Issue_02, Date: 10-09-2017

The information contained herein is as of publication issue. Production processing does not necessarily include testing of all parameters. This documentation is not contractual and content delivery cannot be considered as an offer or contract. Under this document, the Company assumes no obligation towards third parties, liability or guarantee whatsoever.

**ELECTRICAL CHARACTERISTICS**Unless otherwise stated, these specifications apply for $V_{DD} = 3.3V \pm 0.3V$, $-55^{\circ}C < TC < +125^{\circ}C$

SYMBOL	PARAMETER	CONDITION	MIN	MAX	UNIT
TTL/CMOS DC SPECIFICATIONS (EN)					
V_{IH}	High-level input voltage		2.0	5V	V
V_{IL}	Low-level input voltage		-0.3	0.8	V
I_{IH}	High-level input current	$V_{IN} = 3.6V; V_{DD} = 3.6V$	-10	+10	μA
I_{IL}	Low-level input current	$V_{IN} = 0V; V_{DD} = 3.6V$	-10	+10	μA
I_{CS}	Cold Spare Leakage current	$V_{IN} = 3.6V, V_{DD} = V_{SS}$	-3,6	+3,6	μA
LVDS OUTPUT DC SPECIFICATIONS (OUT+, OUT-)					
V_{OD}	Differential Output Voltage	$R_L = 100\Omega$	247	453	mV
ΔV_{OD}	Change in V_{OD} between complementary output states	$R_L = 100\Omega$		10	mV
V_{OS}	Offset Voltage	$R_L = 100\Omega, V_{OS} = \frac{V_{OH} + V_{OL}}{2}$	1.125	1.375	V
ΔV_{OS}	Change in V_{OS} between complementary output states	$R_L = 100\Omega$		50	mV
ΔV_{OSB}	Imbalance of Differential Offset Voltage during Voltage transition	$R_L = 100\Omega, C_L = 1pf$		150	mV
I_{OZ}	Output Tri-State Current	Tri-State output (channel disabled), $V_{OUT} = V_{DD}$ or GND	-20	+20	μA
I_{CSOUT}	Cold Sparing Leakage Current	$V_{OUT} = 3.6V, V_{DD} = V_{SS}$	-20	+20	μA
I_{OS}	Output Short Circuit Current	$V_{OUT+} = V_{OUT-} = 0V$		6	mA
		$V_{OUT+} = V_{OUT-}$		4	mA
LVDS RECEIVER DC SPECIFICATIONS (IN+, IN-)					
V_{TH}	Differential Input High Threshold	$V_{CM} = -4V$ to $+5V$	+100	+600	mV
V_{TL}	Differential Input Low Threshold	$V_{CM} = -4V$ to $+5V$	-600	-100	mV
V_{ID_HYS}	Differential Input hysteresis	$V_{CM} = -4V$ to $+5V$	22	28	mV
V_{ID_FS}	Differential Input Fail-safe threshold	Low Differential Threshold voltage or Open circuit maintained more than 500ns	20		mV
V_{CMR}	Common Mode Voltage Range	$V_{ID} = 350$ mV	-4	+5	V
I_{IN}	Input Current	$V_{DD} = +3.6V, V_{CM} = -4V$ to $+5V, V_{IN+} = V_{TLmin}, V_{IN-} = V_{THmax}$	-10	+10	μA
		$V_{DD} = +3.6V, V_{CM} = -4V$ to $+5V, V_{IN-} = V_{TLmin}, V_{IN+} = V_{THmax}$	-10	+10	μA
ΔI_{IN}	Input Current Balance ($I_{IN+} - I_{IN-}$)	$V_{DD} = +3.6V, V_{CM} = -4V$ to $+5V, V_{IN+} = V_{IN-} = V_{CM}$	-6	6	μA
I_{CSIN}	Cold Sparing Leakage Current	$V_{IN} = +3.6V, V_{DD} = V_{SS}$	-20	+20	μA
SUPPLY CURRENT					
I_{CLLD}	Total Dynamic Supply Current	$R_L = 100\Omega, END/ENCK = V_{DD}, V_{DD} = 3.6V, Fq = 250MHz$		100	mA
I_{CLLS}	Total Static Supply Current	$R_L = 100\Omega, END/ENCK = V_{DD}, V_{DD} = 3.6V, Fq = DC$		80	mA
I_{CCZ}	Tri-State Supply Current	$END, ENCK = V_{SS}, V_{DD} = 3.6V$		10	mA
PSRR	Power Supply Rejection Ratio	$R_L = 100\Omega, END/ENCK = V_{DD}, V_{DD} = 3.6V, Fq = 250MHz$		-50	dB

Table 3: DC Electrical Characteristics

ARQ_12104_DSH_004_Issue_02, Date: 10-09-2017

The information contained herein is as of publication issue. Production processing does not necessarily include testing of all parameters. This documentation is not contractual and content delivery cannot be considered as an offer or contract. Under this document, the Company assumes no obligation towards third parties, liability or guarantee whatsoever.



AC SWITCHING CHARACTERISTICS

Unless otherwise stated, these specifications apply for VDD = 3.3V±0.3V, TA = -55°C to +125°C.

SYMBOL	PARAMETER	CONDITION	MIN	MAX	UNIT
t _{PHZ}	Disable Time (Active to Tri-State) High to Z	R _L = 100Ω, C _L = 10pf		4.5	ns
t _{PLZ}	Disable Time (Active to Tri-State) Low to Z	R _L = 100Ω, C _L = 10pf		4.5	ns
t _{PZH}	Enable Time (Tri-State to Active) Z to High	R _L = 100Ω, C _L = 10pf		250	ns
t _{PZL}	Enable Time (Tri-State to Active) Z to Low	R _L = 100Ω, C _L = 10pf		250	ns
t _{LHT}	Input/Output Low-to-High Transition Time, 20% to 80%	R _L = 100Ω, C _L = 1pf	260	600	ps
t _{HLT}	Input/Output High-to-Low Transition Time, 80% to 20%	R _L = 100Ω, C _L = 1pf	260	600	ps
t _{PLHD}	Propagation Low to High Delay	R _L = 100Ω, C _L = 10pf		3,5	ns
T _{PHLD}	Propagation High to Low Delay	R _L = 100Ω, C _L = 10pf		3,5	ns
T _{SKEW}	Differential Skew T _{PHLD} - T _{PLHD}	R _L = 100Ω, C _L = 10pf		150	ps
T _{CCS}	Output Channel-to-Channel Skew	R _L = 100Ω, C _L = 10pf		500	ps
T _{DDS}	Output Device-to-Device Skew	R _L = 100 Ω, C _L = 10pf		750	ps
t _{PJ}	Periodic Jitter	V _{ID} = 200mV, 50% duty cycle at 200MHz, trise ≤ 1ns (20% - 80%)		15	ps
t _{CCJ}	Cycle to Cycle Jitter	V _{ID} = 200mV, 50% duty cycle at 200MHz, trise ≤ 1ns (20% - 80%)		40	ps
t _{PPJ}	Peak to Peak Jitter	V _{ID} = 27-1 PRBS pattern at 400Mbps, trise ≤ 1ns (20% - 80%)		250	ps
t _{DJ}	Deterministic Jitter	V _{ID} = 27-1 PRBS pattern at 400Mbps, trise ≤ 1ns (20% - 80%)		200	ps

Table 4: AC Electrical Characteristics

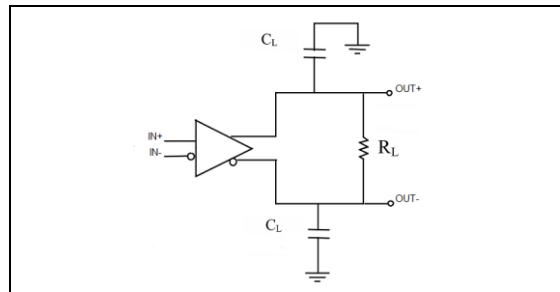


Figure 2: LVDS Output load

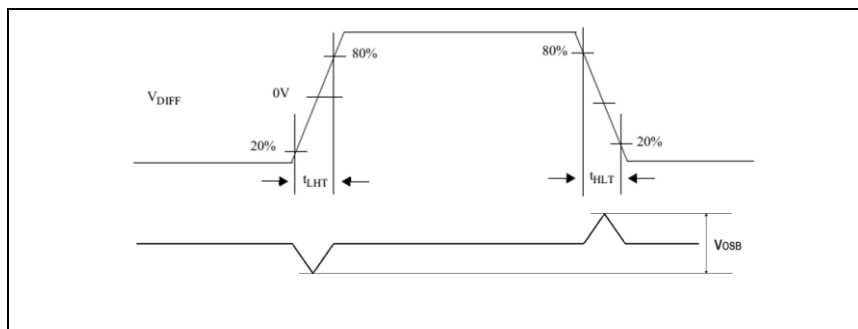


Figure 3: LVDS Output Transition time

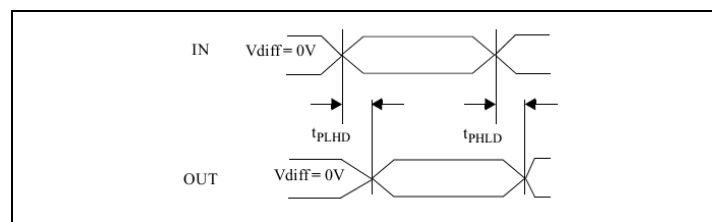


Figure 4: LVDS Propagation delay L->H and H->L

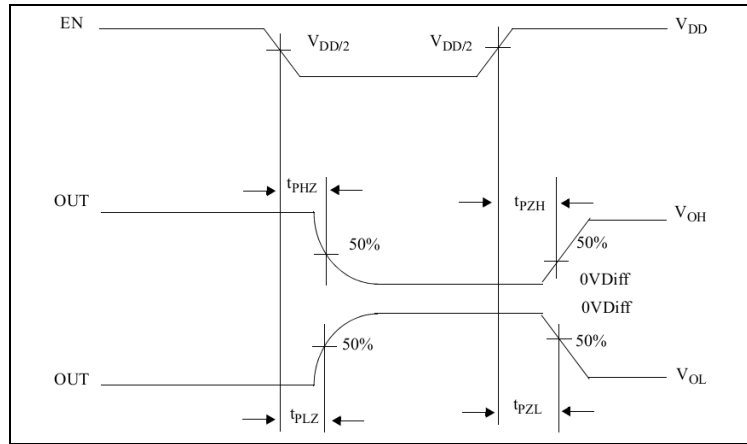


Figure 5: Output active to TRISTATE and TRISTATE to active

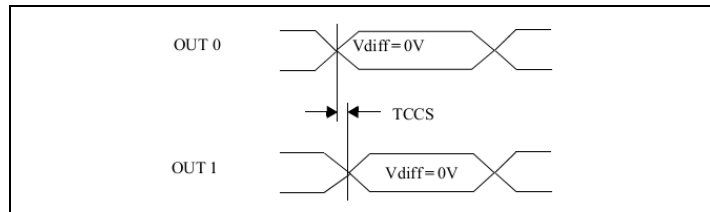


Figure 6: Output channel to channel skew

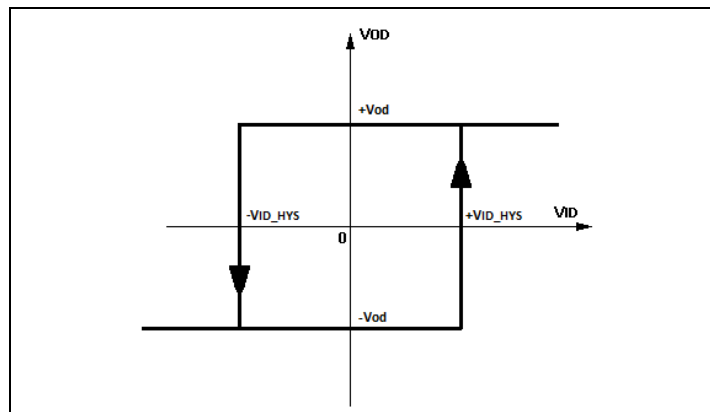


Figure 7: Input Differential Hysteresis



APPLICATIONS INFORMATION

Transmission media:

The transmission media may be printed-circuit board traces, backplanes, or cables. (Note: The ultimate rate and distance of data transfer is dependent upon the attenuation characteristics of the media, the noise coupling to the environment, and other application specific characteristics.)

The signal path should be matched in length to avoid any skew in differential lines or between channels.

Input Fail-Safe (comparator and timer):

The ARQ-LVP001 also supports Fail-Safe operation when OPEN or SHORTED inputs are present. Receiver output goes HIGH after 500ns for all fail-safe conditions.

PCB layout and Power System Bypass:

Circuit board layout and stack-up for the ARQ-LVP001 should be designed to provide noise-free power to the device.

Good layout practice also will separate high frequency or high level inputs and outputs to minimize unwanted stray noise pickup, feedback and interference. Power system performance may be greatly improved by using thin dielectrics (4 to 10 mils) for power/ground sandwiches. This increases the intrinsic capacitance of the PCB power system which improves power supply filtering, especially at high frequencies, and makes the value and placement of external bypass capacitors less

critical. A 0.25Ohm resistor is recommended in the power supply line path. External bypass capacitors should include both RF ceramic and tantalum electrolytic types. RF capacitors may use value of 0.1 μ F. Tantalum capacitors may be 2.2 μ F. Voltage rating for tantalum capacitors should be at least 5X the power supply voltage being used. It is recommended practice to use two vias at each power pin of the ARQ-LVP001, as well as all RF bypass capacitor terminals. Dual vias reduce the interconnect inductance and extends the effective frequency range of the bypass components.

The outer layers of the PCB may be flooded with additional ground plane. These planes will improve shielding and isolation, as well as increase the intrinsic capacitance of the power supply plane system. Naturally, to be effective, these planes must be tied to the ground supply plane at frequent intervals with vias. Frequent via placement also improves signal integrity in signal transmission lines by providing short paths for image currents which reduces signal distortion. The planes should be pulled back from all transmission lines and component mounting pads a distance equal to the width of the widest transmission line from the internal power or ground plane(s) whichever is greater. Doing so minimizes effects on transmission line impedances and reduces unwanted parasitic capacitances at component mounting pads.

ARQ_12104_DSH_004_Issue_02, Date: 10-09-2017

The information contained herein is as of publication issue. Production processing does not necessarily include testing of all parameters. This documentation is not contractual and content delivery cannot be considered as an offer or contract. Under this document, the Company assumes no obligation towards third parties, liability or guarantee whatsoever.



PINOUT DESCRIPTION

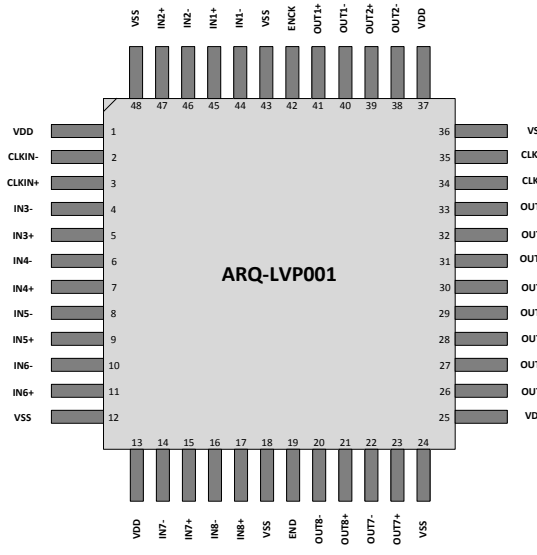


Figure 8: Pinout diagram

No pin	Name	Type	Description
5, 7, 9, 11, 15, 17, 45, 47	INn+	Input	Non-Inverting LVDS input
4, 6, 8, 10, 14, 16, 44, 46	INn-	Input	Inverting LVDS input
21, 23, 27, 29, 31, 33, 39, 41	OUTn+	Output	Non-Inverting LVDS output
20, 22, 26, 28, 30, 32, 38, 40	OUTn-	Output	Inverting LVDS output
19	END	Input	Logic low on enable puts the LVDS data output into Tri-State and reduces supply current
42	ENCK	Input	Logic low on enable puts the LVDS clock output into Tri-State and reduces supply current
12, 18, 24, 36, 43, 48	VSS		Ground
1, 13, 25, 37	VDD		Power supply
3	CLKIN+	Input	Non-Inverting Clock LVDS Input
2	CLKIN-	Input	Inverting Clock LVDS Input
35	CLKO+	Output	Non-Inverting Clock LVDS Output
34	CLKO-	Output	Inverting Clock LVDS Output

Table 5: Pinout description



PACKAGE

CQFP48 Drawing

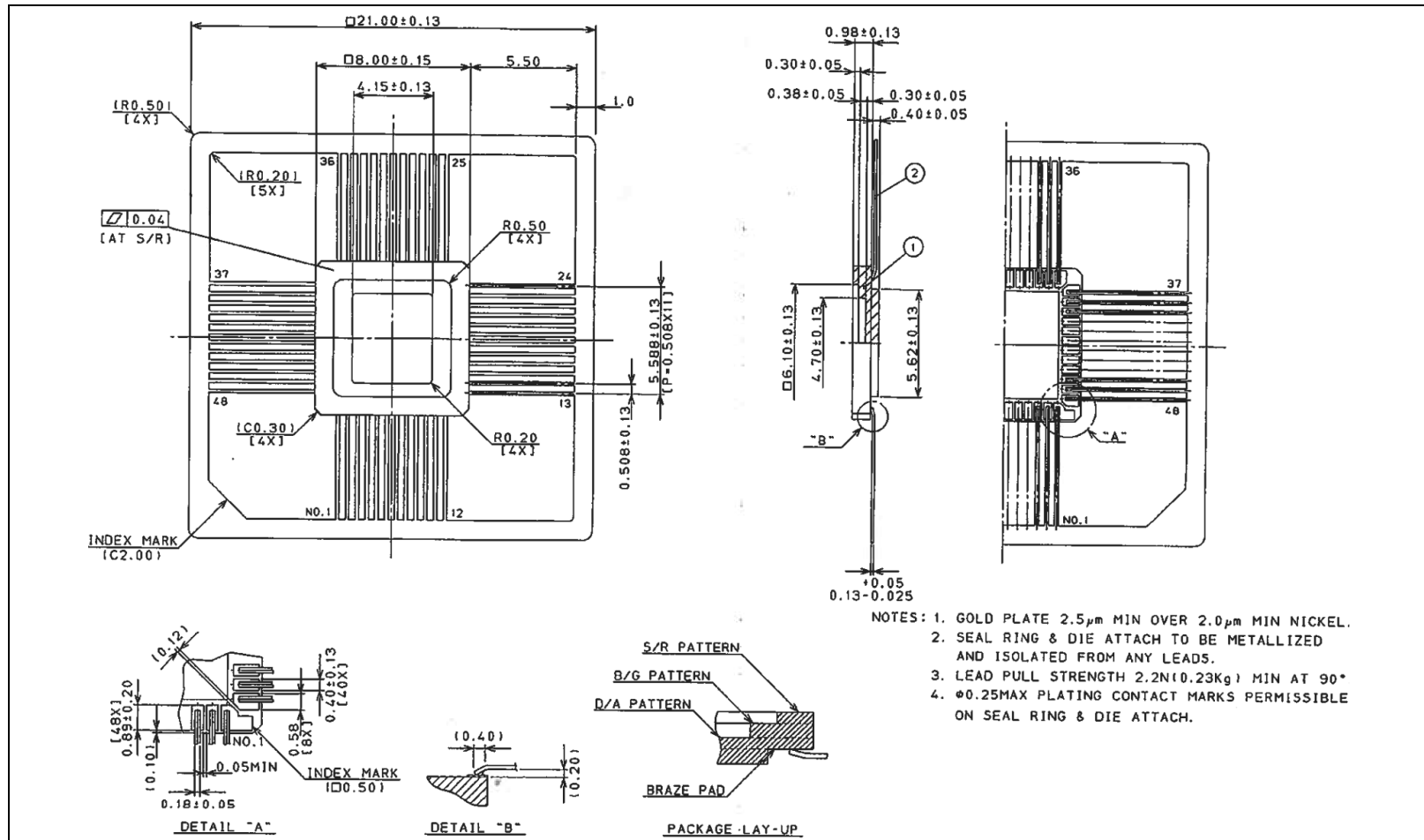


Figure 9: CQFP-48 Package drawing

ARQ_12104_DSH_004_Issue_02, Date: 10-09-2017

The information contained herein is as of publication issue. Production processing does not necessarily include testing of all parameters. This documentation is not contractual and content delivery cannot be considered as an offer or contract. Under this document, the Company assumes no obligation towards third parties, liability or guarantee whatsoever.



QUALITY STANDARDS

ARQUIMEA INGENIERÍA S.L.U. develops its activities under the premises of quality and sustainability, offering efficient, liable and innovative technologies and solutions to its customers.

ARQUIMEA's Quality Management System meets the requirements of ISO 9100:2010 Aerospace Series, and has been audited and certified by the Spanish Association for Standardization and Certification, AENOR.

In order to meet the highest quality and reliability, ARQUIMEA designs and develops its aerospace product line according to military and space standards.



Our space microelectronic devices are available in one or more of the following processes:

- Equivalent to QML 38535 LEVEL Q or Level V*
- Equivalent to ESCC 9000*

For procurement in die form

- In accordance with ECSS-Q-ST-60-05C
- Equivalent to QML 38534 LEVEL H or Level K*

*With Radiation Qualification

ARQ_12104_DSH_004_Issue_02, Date: 10-09-2017

The information contained herein is as of publication issue. Production processing does not necessarily include testing of all parameters. This documentation is not contractual and content delivery cannot be considered as an offer or contract. Under this document, the Company assumes no obligation towards third parties, liability or guarantee whatsoever.

**IMPORTANT NOTICE**

ARQUIMEA INGENIERÍA S.L.U. and its subsidiaries (ARQUIMEA) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers must obtain the latest relevant information before placing orders and must verify that such information is current and complete. All products are sold subject to ARQUIMEA's terms and conditions of sale supplied at the time of order acknowledgment.

ARQUIMEA warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with ARQUIMEA's standard warranty. Testing and other quality control techniques are used to the extent ARQUIMEA deems necessary to support this warranty. Except where mandated by legal requirements, testing of all parameters of each product is not necessarily performed.

ARQUIMEA assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using ARQUIMEA components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

ARQUIMEA does not warrant or represent that any license, either express or implied, is granted under any ARQUIMEA patent right, copyright, mask work right, or other ARQUIMEA intellectual property right relating to any combination, machine, or process in which ARQUIMEA products or services are used. Information published by ARQUIMEA regarding third-party products or services does not constitute a license from ARQUIMEA to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from ARQUIMEA under the patents or other intellectual property of ARQUIMEA.

Reproduction of ARQUIMEA information in ARQUIMEA data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. ARQUIMEA is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of ARQUIMEA products or services with statements different from or beyond the parameters stated by ARQUIMEA for that product or service voids all express and any implied warranties for the associated ARQUIMEA product or service and is an unfair and deceptive business practice. ARQUIMEA is not responsible or liable for any such statements.

ARQUIMEA products are not authorized for use in safety-critical applications (such as life support) where a failure of the ARQUIMEA product would reasonably be expected to cause severe personal injury or death, unless officers of the parties have executed an agreement specifically governing such use. Buyers represent that they have all necessary expertise in the safety and regulatory ramifications of their applications, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of ARQUIMEA products in such safety-critical applications, notwithstanding any applications-related information or support that may be provided by ARQUIMEA. Further, Buyers must fully indemnify ARQUIMEA and its representatives against any damages arising out of the use of ARQUIMEA products in such safety-critical applications.

Only products designated by ARQUIMEA as military-grade or space-grade meet military or space specifications. Buyers acknowledge and agree that any such use of ARQUIMEA products which ARQUIMEA has not designated as military-grade or space-grade is solely at the Buyer's risk and that they are solely responsible for compliance with all legal and regulatory requirements in connection with such use.

ARQ_12104_DSH_004_Issue_02, Date: 10-09-2017

The information contained herein is as of publication issue. Production processing does not necessarily include testing of all parameters. This documentation is not contractual and content delivery cannot be considered as an offer or contract. Under this document, the Company assumes no obligation towards third parties, liability or guarantee whatsoever.

**REVISION HISTORY**

Date Released	Issue	Section	Changes
12-01-2016	Draft A	All	Initial Release copied From ARQ-LVR001 datasheet
23-09-2016	Draft B	ELECTRICAL CHARACTERISTICS	Parameter update after Electrical measurement at Room temperature
		AC SWITCHING CHARACTERISTICS	
13-02-2017	01	FEATURES, APPLICATIONS INFORMATION	Fail-safe feature not available in this version
10-09-2017	02	ELECTRICAL CHARACTERISTICS	Hysteresis feature and Failsafe Threshold Added

ARQ_12104_DSH_004_Issue_02, Date: 10-09-2017

The information contained herein is as of publication issue. Production processing does not necessarily include testing of all parameters. This documentation is not contractual and content delivery cannot be considered as an offer or contract. Under this document, the Company assumes no obligation towards third parties, liability or guarantee whatsoever.



ARQUIMEA

Space Technology Partner

CONTACT AND ORDERS:

ARQUIMEA INGENIERÍA S.L.U.

c/ Margarita Salas 10, 28918 Leganes (Madrid) SPAIN

Tel: +34 91 689 8094

Fax: +34 91 182 1577

Mail: info@arquimea.com

ARQ_12104_DSH_004_Issue_02, Date: 10-09-2017

The information contained herein is as of publication issue. Production processing does not necessarily include testing of all parameters. This documentation is not contractual and content delivery cannot be considered as an offer or contract. Under this document, the Company assumes no obligation towards third parties, liability or guarantee whatsoever.